

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANTS:

Jacobson et al.

SERIAL NO.:

09/590,044

GROUP NO.:

2823

FILING DATE:

June 8, 2000

EXAMINER:

Neal Berezny

TITLE:

METHODS AND APPARATUS FOR MANUFACTURING

BIOELECTRONIC DEVICES

Mail Stop AF Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

Applicants hereby make of record the information contained herein, for consideration by the Examiner in connection with the examination of the above-identified patent application.

The references listed on the enclosed PTO-1449 and enclosed herewith were originally cited in the above-referenced patent application as filed.

It is respectfully requested that each of the references listed on the attached Form PTO-1449, and other information contained herein, be made of record in this application.

Respectfully submitted,

Date: December 2, 2003

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			U.S.	PATENT	DOCUMI	ENTS					
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	A1	5,837,832	11/17/1998	Chee et al	l.						
	A2	5,874,219	02/23/1999	Rava et al	l.						
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